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IN THE CLAIMS

CLAIMS 1-28 (Canceled).

CLAIM 29 (Currently Amended) A method of probing an electronic device component by contacting the electronic device component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic device component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

urging the first substrate and the electronic device component towards one another so that the flexible contact elements make contact with a surface of the electronic component ~~the flexible contact elements have an original shape;~~

the flexible contact elements flex and wipe the surface of the electronic component when the flexible contacts contact the electronic components;
~~and~~

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component~~[[.]]~~ and

at least one of the flexible contact elements includes a protuberance at an end thereof.

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CLAIM 30 (Currently Amended) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to [[60]] 59, wherein the electronic device component is a semiconductor wafer.

CLAIM 31 (Previously Presented) A method according to claim 30, wherein the area is a plurality of integrated circuits on the semiconductor wafer; and the flexible contacts make contact with the plurality of die sites all at once.

CLAIM 32 (Currently Amended) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to [[60]] 59, wherein the area of the electronic device component is a portion of a surface area of the electronic device component.

CLAIM 33 (Currently Amended) A method of probing an electronic device component by contacting the electronic device component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic device component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic device component towards one another so that the flexible contact elements make contact with the electronic component, and the electronic device component is a printed circuit board[[.]] ; and

at least one of the flexible contact elements includes a protuberance at an end thereof.

CLAIM 34 (Currently Amended) A method of probing an electronic device component by contacting the electronic device component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic device component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic device component towards one another so that the flexible contact elements make contact with the electronic component, and the electronic device component is a packaging substrate[.]; and

at least one of the flexible contact elements includes a protuberance at an end thereof.

CLAIM 35 (Currently Amended) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to [[60]] 59, wherein the flexible elements are probe elements.

CLAIM 36 (Currently Amended) A method of probing an electronic device component by contacting the electronic device component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic device component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

urging the first substrate and the electronic device component towards one another so that the flexible contact elements make contact with the electronic component, and at least one of the flexible contact elements further includes a protuberance at an end thereof.

CLAIM 37 (Currently Amended) A method of probing an electronic device component by contacting the electronic device component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic device component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic device component towards one another so that the flexible contact elements make contact with the electronic component, and the flexible elements are wires disposed on the surface of the second substrate, the wires are shaped so that a free end thereof laterally moves when pressed against the area of the electronic device component; and

at least one of the flexible contact elements includes a protuberance at an end thereof.

CLAIM 38 (Currently Amended) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to [[60]] 59, wherein there are electrical connections between the second substrates and the first substrate.

CLAIM 39 (Currently Amended) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to [[60]] 59, wherein the first substrate is a space transformer.

CLAIM 40 (Currently Amended) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to [[60]] 59, wherein the electronic device component is a semiconductor wafer; and the flexible contact elements of the second substrate contact individual semiconductor dies on the semiconductor wafer.

CLAIM 41 (Currently Amended) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to [[60]] 59, wherein the electronic device component is a semiconductor wafer; and the flexible contact elements of the second substrate contacts at least one integrated circuit on the semiconductor wafer.

CLAIM 42 (Currently Amended) A method of probing an electronic device component by contacting the electronic device component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic device component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic device towards one another so that the flexible contact elements make contact with the electronic component so that a free end of the flexible contact elements laterally move when pressed against the area of the electronic device, and the second substrate is aligned to the first substrate by a socket which electrically interconnects the first substrate and the second substrate in a substantially fixed position with respect to each other.

CLAIM 43 (Currently Amended) A method of probing an electronic device component by contacting the electronic device component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic device component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic device component towards one another so that the flexible contact elements make contact with the electronic component so that a free end of the flexible contact elements laterally move when pressed against the area of the electronic device, and the first substrate with the second substrate mounted thereto is mounted to an electrical testing apparatus.

CLAIM 44 (Currently Amended) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to [[60]] 59, wherein the first substrate with the second substrate mounted thereto is mounted to an electrical testing apparatus by a plurality of electrical connections:

CLAIM 45 (Currently Amended) A probe structure comprising an assembly comprising:

a first substrate having a top surface, a bottom surface, a first plurality of terminals disposed on the top surface, and a second plurality of terminals disposed on the bottom surface;

at least one second substrate having a top surface and a bottom surface;

~~means for effecting~~ electrical connections between the at least one second substrate and the first substrate;

a plurality of probe elements disposed on the top surface of the at least one second substrate; and

the probe elements are free-standing flexible conductors shaped so that a free end thereof laterally moves when pressed against a surface.

CLAIM 46 (Previously Presented) A structure according to claim 45, wherein the probe elements are free-standing flexible conductors.

CLAIM 47 (Previously Presented) A structure according to claim 45, wherein protuberances are deposited at ends of the plurality of free-standing flexible conductors.

CLAIM 48 (Previously Presented) A structure according to claim 45, wherein the free-standing flexible conductor further includes a protuberance at an end thereof.

CLAIM 49 (Withdrawn)

CLAIM 50 (Currently Amended) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to [[60]] 59, further including plurality of groups of said plurality of the flexible electrical contact elements.

CLAIM 51 (Currently Amended) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to [[60]] 59, wherein there is a least one of said second ~~substrates~~ substrate is mounted to said first substrate.

CLAIM 52 (Currently Amended) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to [[60]] 59, wherein there are a plurality of said second substrates mounted to said first substrate.

CLAIM 53 (Currently Amended) A method according to claim 33 where each of said plurality of flexible contact elements flex and wipe the area of the electronic device component when said flexible contacts contact the electronic device component; the flexible contact element substantially compliantly respond when the flexible contact element are withdrawn from contacting the electronic device component.

CLAIM 54 (Currently Amended) A method according to claim 34 where each of said plurality of flexible contact elements flex and wipe the area of the electronic device component when said flexible contacts contact the electronic device component; the flexible contact element substantially compliantly respond when the flexible contact element are withdrawn from contacting the electronic device component.

CLAIM 55 (Currently Amended) A method according to claim 36 where each of said plurality of flexible contact elements flex and wipe the area of the electronic device component when said flexible contacts contact the electronic device component; the flexible contact element substantially compliantly respond when the flexible contact element are withdrawn from contacting the electronic device component.

CLAIM 56 (Currently Amended) A method according to claim 37 where each of said plurality of flexible contact elements flex and wipe the area of the electronic device component when said flexible contacts contact the electronic device component; the flexible contact element substantially compliantly respond when the flexible contact element are withdrawn from contacting the electronic device component.

CLAIM 57 (Currently Amended) A method according to claim 42 where each of said plurality of flexible contact elements flex and wipe the area of the electronic device component when said flexible contacts contact the electronic device component; the flexible contact element substantially compliantly respond when the flexible contact element are withdrawn from contacting the electronic device component.

CLAIM 58 (Currently Amended) A method according to claim 43 where each of said plurality of flexible contact elements flex and wipe the area of the electronic device component when said flexible contacts contact the electronic device component; the flexible contact element substantially compliantly respond when the flexible contact element are withdrawn from contacting the electronic device component.

CLAIM 59 (Currently Amended) A probe assembly according to claim 45 wherein said freestanding flexible conductors are shaped to flex and wipe the area of the electronic device component; the freestanding flexible conductors substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component.

CLAIM 60 – 87 (Withdrawn)

CLAIM 88 (Currently Amended) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43, 49 or 53 to 59 wherein ~~said freestanding~~ the flexible conductors comprise a coating.

CLAIM 89 (Previously Presented) A structure according to claim 88 wherein said coating is selected from the group consisting of Au, Cr, Co, Ni and Pd.

CLAIM 90 (Previously Presented) A structure according to claim 89 wherein said free standing flexible conductor comprises gold, gold alloy, copper, copper alloy, aluminum, nickel, palladium and platinum.

CLAIM 91 (New) A method according to claim 42 wherein at least one of the flexible contact elements further include a protuberance at an end thereof.

CLAIM 92 (New) A method according to claim 43 wherein at least one of the flexible contact elements further includes a protuberance at an end thereof.

CLAIM 93 (New) A method according to any one of claims 29, 33, 34, 36, 37, 91 or 92 wherein the protuberance comprises a surface having a portion which is substantially spherical.

CLAIM 94 (New) A method according to any one of claims 29, 33, 34, 36, 37, 91 or 92 wherein the protuberance comprises a substantially planar surface.

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CLAIM 95 (New) A method according to claim 94 wherein the substantially planar surface comprises a projection.

CLAIM 96 (New) A method according to claim 95 wherein the projection comprises a shape selected from the group consisting of a hemispherical shape, a rectangular shape and a pyramidal shape.

CLAIM 97 (New) A method according to claim 96 wherein the projection provides a region which can wipe on the surface of the electronic component.

CLAIM 98 (New) A method according to claim 97 wherein the surface of the electronic component is an electrically conductive pad over which said projection wipes to make good electrical contact therewith.

CLAIM 99 (New) A method according to any one of claims 29, 33, 36, 37, 91 to 97 or 98 wherein the flexible contact elements comprise a coating.

CLAIM 100 (New) A method according to claim 99 wherein the coating is selected from the group consisting of Au, Cr, Co, Ni and Pd.

CLAIM 101 (New) A method according to claim 99 wherein the flexible contact element comprises a material selected from the group consisting of gold, gold alloy, copper, copper alloy, aluminum, nickel, palladium and platinum.

CLAIM 102 (New) A method according to claim 100 wherein the flexible contact element comprises a material selected from the group consisting of gold, gold alloy, copper, copper alloy, aluminum, nickel, palladium and platinum.

CLAIM 103 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, the substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with a surface of the electronic component;

the flexible contact elements flex and wipe the surface of the electronic component when the flexible contacts contact the electronic components;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component; and

said electronic component is a semiconductor wafer.

CLAIM 104 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, the substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, the second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, the first substrate comprises a printed circuit board; and

said electronic component is a semiconductor wafer.

CLAIM 105 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and the second substrate comprises a packaging substrate; and

said electronic component is a semiconductor wafer.

CLAIM 106 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and the flexible elements are wires disposed on the surface of the second substrate, the wires are shaped so that a free end thereof laterally moves when pressed against the area of the electronic component; and

said electronic component is a semiconductor wafer.

CLAIM 107 (New) A method according to any one of claims 103 to 105 or 106, wherein the area is a plurality of integrated circuits on the semiconductor wafer; and the flexible contacts make contact with the plurality of die sites all at once.

CLAIM 108 (New) A method according to any one of claims 103 to 105 or 106 where each of said plurality of flexible contact elements flex and wipe the area of the electronic component when said flexible contacts contact the electronic component; the flexible contact element substantially compliantly respond when the flexible contact element are withdrawn from contacting the electronic component.

CLAIM 109 (New) A method of probing an electronic component by contacting the electronic device with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with a surface of the electronic component;

the flexible contact elements flex and wipe the surface of the electronic component when the flexible contacts contact the electronic components;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

the electronic component is a semiconductor wafer; and

the flexible contact elements of the second substrate contact individual semiconductor dies on the semiconductor wafer.

CLAIM 110 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and the first substrate comprises a printed circuit board; and

the electronic component is a semiconductor wafer; and the flexible contact elements of the second substrate contact individual semiconductor dies on the semiconductor wafer.

CLAIM 111 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and the second substrate comprises is a packaging substrate; and

the electronic component is a semiconductor wafer; and the flexible contact elements of the second substrate contact individual semiconductor dies on the semiconductor wafer.

CLAIM 112 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and the flexible elements are wires disposed on the surface of the second substrate, the wires are shaped so that a free end thereof laterally moves when pressed against the area of the electronic component; and

the electronic component is a semiconductor wafer; and the flexible contact elements of the second substrate contact individual semiconductor dies on the semiconductor wafer.

CLAIM 113 (New) A method according to any one of claims 109 to 111 or 112 where each of said plurality of flexible contact elements flex and wipe the area of the electronic component when said flexible contacts contact the electronic component; the flexible contact element substantially compliantly respond when the flexible contact element are withdrawn from contacting the electronic component.

CLAIM 114 (New) A method of probing an electronic component by contacting the electronic device with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with a surface of the electronic component;

the flexible contact elements flex and wipe the surface of the electronic component when the flexible contacts contact the electronic components;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component; and

the electronic component is a semiconductor wafer; and the flexible contact elements of the second substrate contacts at least one integrated circuit on the semiconductor wafer.

CLAIM 115 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and the first substrate comprises a printed circuit board; and

the electronic component is a semiconductor wafer; and the flexible contact elements of the second substrate contacts at least one integrated circuit on the semiconductor wafer.

CLAIM 116 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the

electronic component, and the second substrate comprises is a packaging substrate; and

the electronic component is a semiconductor wafer; and the flexible contact elements of the second substrate contacts at least one integrated circuit on the semiconductor wafer.

CLAIM 117 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and the flexible elements are wires disposed on the surface of the second substrate, the wires are shaped so that a free end thereof laterally moves when pressed against the area of the electronic component; and

the electronic component is a semiconductor wafer; and the flexible contact elements of the second substrate contacts at least one integrated circuit on the semiconductor wafer.

CLAIM 118 (New) A method according to any one of claims 114 to 116 or 117 where each of said plurality of flexible contact elements flex and wipe the area of the electronic component when said flexible contacts contact the electronic component; the flexible contact element substantially compliantly respond when the flexible contact element are withdrawn from contacting the electronic component.

CLAIM 119 (New) A method of probing an electronic component by contacting the electronic device with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with a surface of the electronic component;

the flexible contact elements flex and wipe the surface of the electronic component when the flexible contacts contact the electronic components;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component; and

there is at least one second substrate mounted to the first substrate.

CLAIM 120 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and the first substrate comprises a printed circuit board; and

there is at least one second substrate mounted to the first substrate.

CLAIM 121 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and second substrate comprises a packaging substrate; and

there is at least one second substrate mounted to the first substrate.

CLAIM 122 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and the flexible elements are wires disposed on the surface of the second substrate, the wires are shaped so that a free end thereof laterally moves when pressed against the area of the electronic component; and

there is at least one second substrate mounted to the first substrate.

CLAIM 123 (New) A method according to any one of claims 119 to 121 or 122 where each of said plurality of flexible contact elements flex and wipe the area of the electronic component when said flexible contacts contact the electronic component; the flexible contact element substantially compliantly respond when the flexible contact element are withdrawn from contacting the electronic component.

CLAIM 124 (New) A method of probing an electronic component by contacting the electronic device with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

urging the first substrate and the electronic device towards one another so that the flexible contact elements make contact with a surface of the electronic component;

the flexible contact elements flex and wipe the surface of the electronic component when the flexible contacts contact the electronic components;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component; and

there are a plurality of the second substrates mounted to the first substrate.

CLAIM 125 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and the first substrate comprises a printed circuit board; and

there are a plurality of the second substrates mounted to the first substrate.

CLAIM 126 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and the second substrate comprises a packaging substrate; and

there are a plurality of the second substrates mounted to the first substrate.

CLAIM 127 (New) A method of probing an electronic component by contacting the electronic component with a plurality of flexible contact elements, the method comprising the steps of:

providing a first substrate corresponding to an area of the electronic component to be probed, said substrate having a front surface;

mounting and connecting a second substrate to the front surface of the first substrate, said second substrate having a plurality of flexible contact elements bonded to and extending from a surface thereof;

the flexible contact elements substantially compliantly respond when the flexible contact elements are withdrawn from contacting the electronic component;

urging the first substrate and the electronic component towards one another so that the flexible contact elements make contact with the electronic component, and the flexible elements are wires disposed on the surface of the second substrate, the wires are shaped so that a free end thereof laterally moves when pressed against the area of the electronic component; and

there are a plurality of the second substrates mounted to the first substrate.

CLAIM 128 (New) A method according to any one of claims 124 to 126 or 127 where each of said plurality of flexible contact elements flex and wipe the area of the electronic component when said flexible contacts contact the electronic component; the flexible contact element substantially compliantly respond when the flexible contact element are withdrawn from contacting the electronic component.

CLAIM 129 (New) A method according to any one of claims 103 to 127 or 128 wherein at least one of the flexible contact elements further include a protuberance at an end thereof.

CLAIM 130 (New) A method according to claim 129, wherein the protuberance comprises a surface having a portion which is substantially spherical.

CLAIM 131 (New) A method according to claim 129 wherein the protuberance comprises a substantially planar surface.

CLAIM 132 (New) A method according to claim 131 wherein the substantially planar surface comprises a projection.

CLAIM 133 (New) A method according to claim 132 wherein said projection comprises a shape selected from the group consisting of a hemispherical shape, a rectangular shape and a pyramidal shape.

CLAIM 134 (New) A method according to claim 133 wherein said projection provides a region which can wipe on the surface of the electronic component.

CLAIM 135 (New) A method according to claim 134 wherein the surface is an electrically conductive pad over which said projection wipes to make good electrical contact therewith.

CLAIM 136 (New) A method according to any one of claims 103 to 135 or 136 wherein the flexible contact elements comprise a coating.

CLAIM 137 (New) A method according to claim 136 wherein the coating is selected from the group consisting of Au, Cr, Co, Ni and Pd.

CLAIM 138 (New) A method according to claim 136 wherein the flexible contact element comprises a material selected from the group consisting of gold, gold alloy, copper, copper alloy, aluminum, nickel, palladium and platinum.

CLAIM 139 (New) A method according to claim 137 wherein the flexible contact element comprises a material selected from the group consisting of gold, gold alloy, copper, copper alloy, aluminum, nickel, palladium and platinum.